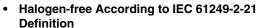


# BSC035N04LS G-VB Datasheet N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
40	0.0025 at V <sub>GS</sub> = 10 V	120	38 nC		
40	0.0028 at V <sub>GS</sub> = 6.5 V	105	30 110		

#### **FEATURES**



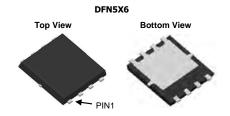


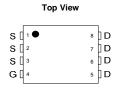
COMPLIANT

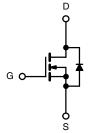
- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested

#### **APPLICATIONS**

- Synchronous Rectification
- Secondary Side DC/DC







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	$V_{DS}$	40	V		
Gate-Source Voltage	V <sub>GS</sub>	± 20	v		
	$T_C = 25 ^{\circ}C$ $T_C = 70 ^{\circ}C$		120		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	80 33 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		26 <sup>b, c</sup>	A	
Pulsed Drain Current		I <sub>DM</sub>	360		
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	100		
Continuous Course Brain Blode Current	T <sub>A</sub> = 25 °C	.0	4.9 <sup>b, c</sup>		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	40		
Single Pulse Avalanche Energy	L = 0.1 IIII1	E <sub>AS</sub>	80	mJ	
	T <sub>C</sub> = 25 °C		83		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	53	w	
Maximum i Ower Dissipation	T <sub>A</sub> = 25 °C	υ' υ	5.4 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		3.4 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		
Soldering Recommendations (Peak Temperature	_	260			

THERMAL RESISTANCE RATINGS								
Parameter	Symbol	Typical	Maximum	Unit				
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	R <sub>thJA</sub>	18	23	°C/W			
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	1.0	1.5	] 0/W			

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 80 A.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	40			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050A		43		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 6		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Wallana Bua'a Oamant	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V			1	μΑ
Zero Gate Voltage Drain Current		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	100			Α
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A		0.0025		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =6.5 V, I <sub>D</sub> = 20 A		0.0028		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 20 A		102		S
Dynamic <sup>b</sup>						1
Input Capacitance	C <sub>iss</sub>			4750		pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V, f = 1 MHz		610		
Reverse Transfer Capacitance	C <sub>rss</sub>			275		
		V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A		78	117	nC
Total Gate Charge	$Q_g$			38	57	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 20 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$		13		
Gate-Drain Charge	$Q_{gd}$			11		
Gate Resistance	$R_g$	f = 1 MHz	0.2	0.7	1.4	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			14	25	ns
Rise Time	t <sub>r</sub>	$V_{DD} = 20 \text{ V}, R_L = 2 \Omega$		9	18	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		41	65	
Fall Time	t <sub>f</sub>			9	18	
Turn-On Delay Time	t <sub>d(on)</sub>			33	42	115
Rise Time	t <sub>r</sub>	$V_{DD} = 20 \text{ V}, R_L = 2 \Omega$		22	35	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		42	65	
Fall Time	t <sub>f</sub>			13	25	
Drain-Source Body Diode Characteris	stics					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C		50		A
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			60		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 5 A		0.75	1.1	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			40	60	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 10 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		48	72	nC
everse Recovery Fall Time t <sub>a</sub>		$F = 10 \text{ A}, \text{ al/at} = 100 \text{ A/} \mu \text{s}, \text{ fg} = 25 \text{ C}$		24		
Reverse Recovery Rise Time	t <sub>b</sub>	7		16		ns

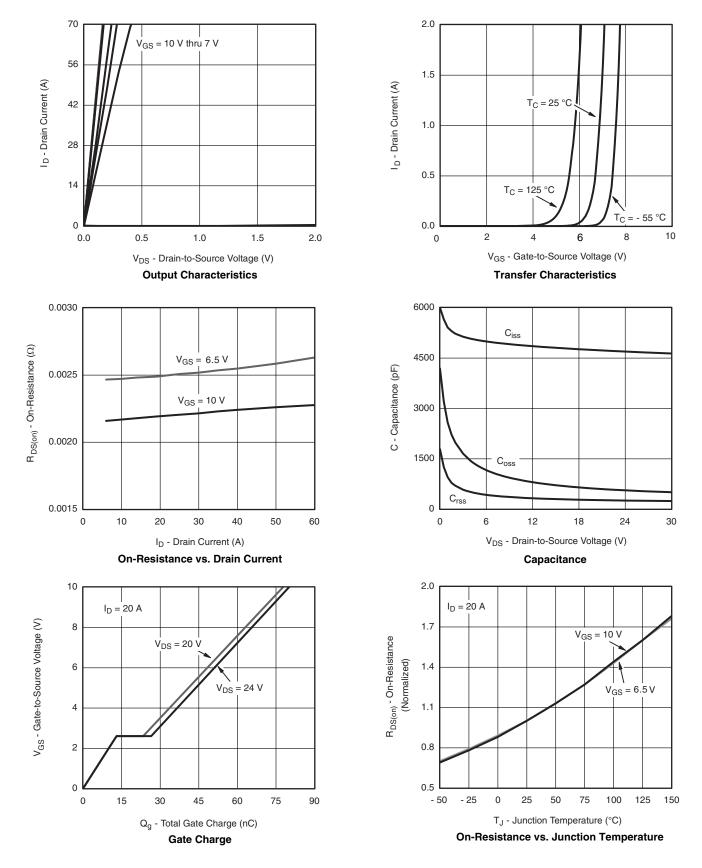
#### Notes

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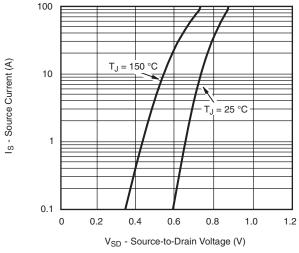
- a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.

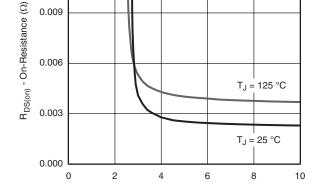
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.









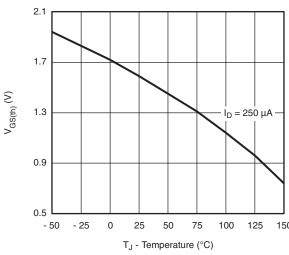


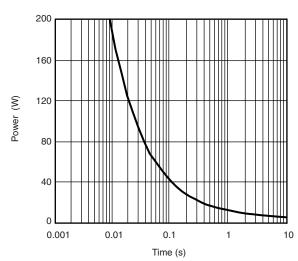
0.012

0.009

#### Source-Drain Diode Forward Voltage

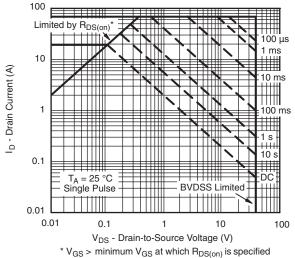






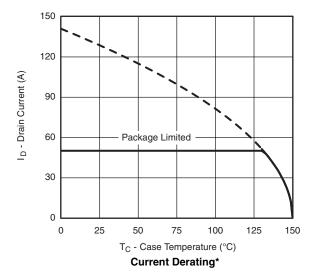
#### **Threshold Voltage**

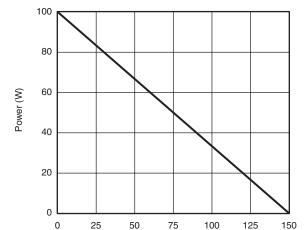
Single Pulse Power, Junction-to-Ambient

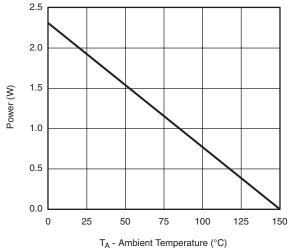


Safe Operating Area, Junction-to-Ambient









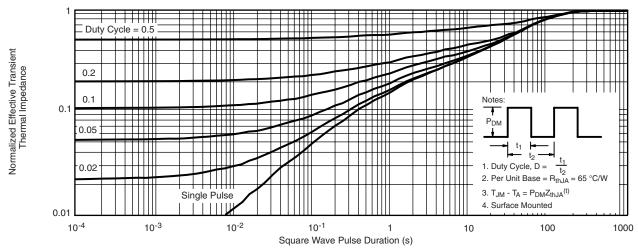
T<sub>C</sub> - Case Temperature (°C)

Power, Junction-to-Case

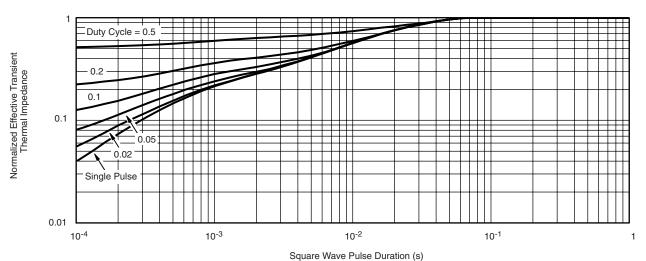
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





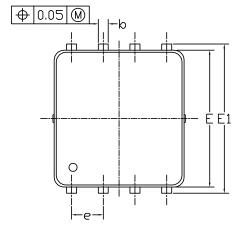
#### Normalized Thermal Transient Impedance, Junction-to-Ambient

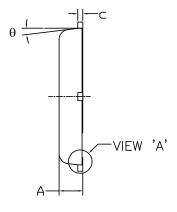


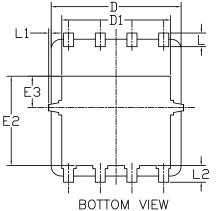
Normalized Thermal Transient Impedance, Junction-to-Case

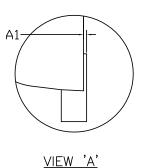


DFN5x6\_8L\_EP1\_P PACKAGE OUTLIN



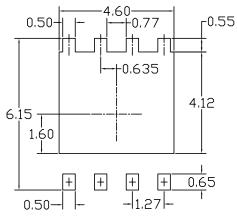






(SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.85	0. 95	1.00	0.033	0.037	0.039
A1	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
c	0. 15	0. 20	0. 25	0.006	0.008	0.010
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209
D1	4. 25	4. 35	4. 45	0. 167	0.171	0. 175
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242
E2	3. 525	3. 625	3. 725	0. 139	0. 143	0. 147
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054
e	1. 27 BSC			0.050 BSC		
L	0.45	0. 55	0.65	0.018	0.022	0.026
L1	0		0.15	0		0.006
L2	0.68 REF			0. 027 REF		
θ	0°		10°	0°		10°

### NOTE

- UNIT: mm
- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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